

Yannick Guhel

List of Publications by Year in descending order

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Version: 2024-02-01

15
papers

105
citations

1478505

6
h-index

1372567

10
g-index

15
all docs

15
docs citations

15
times ranked

137
citing authors

#	ARTICLE	IF	CITATIONS
1	Raman Study of the Comparative Effects of Conventional and Microwave Annealing on MgTiO ₃ Thin Films Sputtered on Si Substrate. Physica Status Solidi (A) Applications and Materials Science, 2022, 219, .	1.8	0
2	Evolution over time of mackinawite generated on carbon steel by the SRB metabolic activity: an in-operando Raman study. Biofouling, 2022, 38, 271-285.	2.2	1
3	Improvement of humidity sensing performance of BiFeO ₃ nanoparticles-based sensor by the addition of carbon fibers. Sensors and Actuators A: Physical, 2020, 307, 111981.	4.1	15
4	Measurement of Self-Heating Temperature in AlGaIn/GaN HEMTs by Using Cerium Oxide Micro-Raman Thermometers. IEEE Transactions on Electron Devices, 2019, 66, 4156-4163.	3.0	6
5	Neutron Irradiation Effects on the Electrical Properties of Previously Electrically Stressed AlInN/GaN HEMTs. IEEE Transactions on Nuclear Science, 2019, 66, 810-819.	2.0	1
6	First results of humidity sensors based on CeO ₂ thick film deposited by a new deposition technique from a suspension of nanoparticles. Microelectronic Engineering, 2019, 207, 7-14.	2.4	8
7	Influence of neutron irradiation on electron traps induced by NGB stress in AlInN/GaN HEMTs. IEEE Transactions on Nuclear Science, 2017, , 1-1.	2.0	2
8	Analysis of degradation mechanisms in AlInN/GaN HEMTs by electroluminescence technique. Solid-State Electronics, 2017, 127, 13-19.	1.4	4
9	Innovative submicron thermal characterization method for AlGaIn/GaN power HEMTs with hyperspectral thermoreflectance imaging. , 2017, , .		3
10	Impact of microwave annealing on CeO ₂ thin films sputtered on (111) Si. Materials Research Bulletin, 2015, 70, 712-718.	5.2	4
11	Rapid thermal annealing of cerium dioxide thin films sputtered onto silicon (111) substrates: Influence of heating rate on microstructure and electrical properties. Materials Science in Semiconductor Processing, 2015, 30, 352-360.	4.0	6
12	In situ Raman characterization of CeO ₂ thin films sputtered on (111) Si in order to optimize the post growth annealing parameters. Microelectronic Engineering, 2014, 118, 29-34.	2.4	8
13	Characterization and analysis of electrical trap related effects on the reliability of AlGaIn/GaN HEMTs. Solid-State Electronics, 2012, 72, 15-21.	1.4	14
14	Characterization of the self-heating of AlGaIn/GaN HEMTs during an electrical stress by using Raman spectroscopy. Microelectronics Reliability, 2011, 51, 1796-1800.	1.7	16
15	Raman characterization before and after rapid thermal annealing of CeO ₂ thin films grown by rf sputtering on (111) Si. Journal of Raman Spectroscopy, 2009, 40, 401-404.	2.5	17